The Radial Velocity (RV) Method for the Detection of Exoplanets

Artie P. Hatzes

Thüringer Landessternwarte Tautenburg

artie@tls-tautenburg.de



Outline of RV Lectures

- 1. Instrumentation: Detectors and Spectrographs
- 2. Precise Stellar Radial Velocity Measurements
- 3. Frequency Analysis: Detecting Periodic Signals in Time Series Data
- 4. Keplerian Orbits
- 5. Sources of Errors: Instrumental and Stellar
- 6. Dealing with the Activity Signal





RV precision of 10 cm/s by 2023!

This was achieved by a combination of:

- 1. CCD Detectors
- 2. Cross-dispersed echelle spectrographs
- 3. Better wavelength calibration
- 4. Reduction of instrumental shifts

Charge Coupled Devices



- Quantum Efficiency of 80-90% (Photographic plates ~1%) → Higher
 S/N data
- 2-D Arrays → Perfect match to echelle spectrographs
- Data in digital form \rightarrow easier manipulation of data

The Basic Unit of a CCD: The Pixel



The basic element of a CCD consists of a Metal Oxide Semiconductor. The bulk material is p-silicon on which an insulating layer of silicon oxide has been grown as well as thin conducting electrodes of transparent polysilicon. The central electrode is set to a positive bias while the two flanking electrodes are negative. This creates a <u>"depletion" region</u> under the central electrode containing no holes but a deep potential well to trap electrons. The region shown is about 10µ thick. During exposure light enters through the "front-side" electrodes. Photoelectrons generated under the central electrode will be attracted toward the electrode and held below it. The corresponding holes will be swept away into the bulk silicon.

Reading out a CCD



A "3-phase CCD"

Parallel registers shift the charge along columns

There is one serial register at the end which reads the charge along the final row and records it to a computer

For last row, shift is done along the row



Figure from O'Connell's lecture notes on detectors

The CCD is first clocked along the parallel register to shift the charge down a column

The CCD is then clocked along a serial register to readout the last row of the CCD

The process continues until the CCD is fully read out.

How much charge is lost in the this charge transfer process?

Typical Charge Transfer Efficiency of a CCD is >99.999 %

Suppose you have a 4096 x 4096 CCD and detect 40.000 photons (electrons). Signal to Noise ratio = \sqrt{N} = 200

Charge recorded = $40.000 \times 0.99999^{4096} = 38.394$

1605 electrons "lost"

S/N decreased to 195

CCD Parameters Important for Observations

• Gain: Converts ADU to number of photons detected. Important for Signal-to-Noise estimate. Typically $0.5-10 e^{-1}/ADU$

• Linearity: Detected counts should be proportional to the exposure time. If a CCD has a non-linear regime these level of counts should be avoided

• Readout Noise: Noise introduced by CCD readout electronics. Negligible for High Signal-to Noise observations

• Dark: Thermal noise. Neglible for High Signal-to-Noise Observations Most science grades CCDs are kept at –120 C or cooler.

• Bias level: Constant level added to the data by the electronics to ensure that there are no negative numbers

McDonald CCD for coude spectrograph:

Gain = $0.56 \pm 0.015 e^{-1}/ADU$

Readout Noise = 3.06 electrons

Bias level = 1024

Noise Tests for CCD: Linearity

Take a series of frames of a low intensity lamp and plot the mean counts as a function of exposure time



If the curve followed the red line at the high count rate end (and some CCDs do!) then you would know to keep your exposure to under 150.000

Problems and Pitfalls of CCD Usage

Saturation

If too many electrons are produced (too high intensity level) then the full well of the CCD is reached and the maximum count level will be obtained. Additional detected photons will not increase the measured intensity level:



Problems and Pitfalls of CCDs

Blooming:

If the full well is exceeded then charge starts to spill over in the readout direction, i.e. columns. This can destroy data far away from the saturated pixels.



The charge capacity of a CCD pixel is limited, when a pixel is full the charge starts to leak into adjacent pixels. This process is known as 'Blooming'.



Anti-blooming CCD can eliminate this effect:



Blooming

No blooming

One solution: Anti-blooming CCDs



Residual Images



If the intensity is too high this will leave a residual image. Left is a normal CCD image. Right is a bias frame showing residual charge in the CCD. This can effect photometry and spectroscopy.

Solution: several dark frames readout or shift image between successive exposures

Fringing

CCDs especially back illuminated ones are bonded to a glass plate



When the glass is illuminated by monochromatic light it creates a fringe pattern. Fringing can also occur without a glass plate due to the thickness of the CCD

λ (Å)



Depending on the CCD fringing becomes important for wavelengths greater than about 6500 Å

Readout Noise



High readout noise CCDs (older ones) could seriously affect the Signal-to-Noise ratios of observations

Basic CCD reductions

- Subtract the Bias level. The bias level is an artificial constant added in the electronics to ensure that there are no negative pixels
- Divide by a Flat lamp to ensure that there are no pixel to pixel variations
- Optional: Removal of cosmic rays. These are high energy particles from space that create "hot pixels" on your detector. Also can be caused by natural radioactive decay on the earth.

For Spectral Observations:

- Global scattered light subtraction
- Order tracing and fitting
- Order extraction
- Wavelength calibration using (typically) a Th-Ar hollow cathode lamp

Bias



Pixel

Most CCDs have an overscan region, a portion of the chip that is not exposed so as to record the bias level. The prefered way is to record a separate bias (a dark with 0 sec exposure) frame and fit a surface to this. This is then subtracted from every frame as the first step in the reduction. If the bias changes with time then it is better to use the overscan region

Flat Field Division



Raw Frame

Flat Field

Raw divided by Flat

Every CCD has different pixel-to-pixel sensitivity, defects, dust particles, etc that not only make the image look bad, but if the sensitivity of pixels change with time can influence your results. *Every* observation must be divided by a flat field after bias subtraction. The flat field is an observation of a white lamp. For imaging one must take either sky flats, or dome flats (an illuminated white screen or dome observed with the telescope). For spectral observations "internal" lamps (i.e. ones that illuminate the spectrograph, but not observed through the telescope are taken. Often even for spectroscopy "dome flats" produce better results, particularly if you want to minimize fringing.





Spectrographs



Spectral Resolution



Consider two monochromatic beams

They will just be resolved when they have a wavelength separation of $d\lambda$

Resolving power:

$$R = \frac{\lambda}{d\lambda}$$

 $d\lambda$ = full width of half maximum of calibration lamp emission lines



R = 15.000

R = 100.000

R = 500.000





R = 3.000

We will see that RV measurements benefit from high resolution



Without the grating a spectograph is just an imaging camera

A spectrograph is just a camera which produces an image of the slit at the detector. The dispersing element produces images as a function of wavelength





Plate Factor

$$\mathsf{P} = (f\mathsf{A})^{-1} = (f\frac{\mathsf{d}\beta}{\mathsf{d}\lambda})^{-1}$$

A is your dispersion

P is in Angstroms/mm

P x CCD pixel size = Ang/pixel



- D = Diameter of telescope d_1 = Diameter of collimator d_2 = Diameter of camera
- f = Focal length of telescope
- f_1 = Focal length of collimator
- f_2 = Focal length of camera
- A = Dispersing element



w = slit width h = slit height Entrance slit subtends an angle ϕ and ϕ' on the sky: $\phi = w/f$ $\phi' = h/f$

Entrance slit subtends an angle $\delta \alpha$ and $\delta \alpha'$ on the collimator: $\delta \alpha = w/f_1$ $\delta \alpha' = h/f_1$

w' =
$$rw(f_2/f_1) = r\phi DF_2$$

h' = $h(f_2/f_1) = \phi' DF_2$

 $F_2 = f_2/d_1$ r = anamorphic magnification due to dispersing element = d_1/d_2

$$w' = rw(f_2/f_1) = r\phi DF_2$$

This expression is important for matching slit to detector: $2\Delta = r\phi DF_2$ for Nyquist sampling (2 pixel projection of slit). 1 CCD pixel (Δ) typically 15 – 20 µm

Example 1:

$$\phi = 1 \text{ arcsec}, D = 2m, \Delta = 15 \mu m \Rightarrow rF_2 = 3.1$$

Example 2:

$$\phi = 1 \text{ arcsec}, D = 4m, \Delta = 15 \mu m => rF_2 = 1.5$$

Example 3:

$$\phi = 0.5 \text{ arcsec}, D = 10m, \Delta = 15 \mu m \Rightarrow rF_2 = 1.2$$

Example 4:

$$\phi = 0.1 \text{ arcsec}, D = 100 \text{m}, \Delta = 15 \mu \text{m} => \text{rF}_2 = 0.6$$



The Grating Equation





Fig. 3.9. Eq. (3.11) gives this scalar-wave blaze distribution of light. The first three orders are shown for $\phi = 20^{\circ}$.



Fig. 3.10. Here the blaze distributions of Fig. 3.9 are plotted on a wavelength scale using $\alpha = \phi - 20^{\circ}$.

Angular Dispersion:

$$\frac{d\beta}{d\lambda} = \frac{m}{\sigma\cos\beta} = \frac{\sin\alpha + \sin\beta}{\lambda\cos\beta}$$

Linear Dispersion:

$$\frac{d\lambda}{dx} = \frac{d\lambda}{d\beta} \frac{d\beta}{dx} = \frac{1}{f_{cam}} \frac{1}{d\beta/d\lambda}$$
Angstroms/mm

Resolving Power

$$dx = f_2 \quad \frac{d\beta}{d\lambda} \quad \Delta\lambda$$

$$w' = rw(f_2/f_1) = r\phi DF_2$$

$$f_2 \quad \frac{d\beta}{d\lambda} \quad \Delta\lambda = r\phi DF_2$$
Recall: $F_2 = f_2/d_1$

$$\delta\lambda = -\frac{r\phi}{A} \quad \frac{D}{d_1}$$
For a given telescope R depends only on collimator diameter
$$R = \lambda/d\lambda = -\frac{\lambda A}{r} \quad \frac{1}{\phi} \quad \frac{d_1}{D}$$

R = 100.000

$$A = 1.7 \times 10^{-3}$$

D(m)	φ (arcsec)	d ₁ (cm)
2	1	10
4	1	20
10	1	52
10	0.5	26
30	0.5	77
30	0.25	38



What if adaptive optics can get us to the diffraction limit?

Slit width is set by the diffraction limit:



Normal gratings:

- ruling 600-1200 grooves/mm
- Used at low blaze angle (~10-20 degrees)
- orders m=1-3

Echelle gratings:

- ruling 32-80 grooves/mm
- Used at high blaze angle (~65 degrees)
- orders m=50-120

242	13. Dispersing Elements and Systems			
		m	$1/\sigma$ (mm)	δ (°)
	First-order grating	1	1200	17.5
	Echelle	45	79	63.5
	$\alpha = \delta + \theta,$	$\beta = \delta - \theta,$	$\theta > 0$ if $\alpha > \beta$	

Both satisfy grating equation for λ = 5000 A





You want to observe λ_1 in order m=1, but light λ_2 at order m=2, where $\lambda_1 \neq \lambda_2$ contaminates your spectra

Order blocking filters must be used

79 gr/mm grating

Schematic: orders separated in the vertical direction for clarity



In reality:



Need interference filters but why throw away light?

Spectrographs







 $\Delta y \propto \lambda^2$ Grating cross-dispersed echelle spectrographs

Prism cross-dispersed echelle spectrographs



Cross dispersion



Increasing wavelength



Blaze Function:

$$I = IF \times BF = \frac{\sin^2 N\gamma' \sin^2 \gamma}{\sin^2 \gamma' \gamma^2}$$

 $2\gamma' =$ phase difference between center of adjacent grooves

 γ = phase diference between center and edge of one groove.

III. Grating Efficiency



Fig. 13.6. Intensity pattern of single diffracted wavelength for grating in Fig. 13.5. BF, Blaze function; IF, interference factor.



$\theta \neq 0$:

Blaze function is determined by the effective width of a single groove \Rightarrow depends on θ .



$$b' = \sigma cos \alpha / cos \beta$$



Choice of θ depends on mechanical constraints, desired efficiency, shape of blaze function, and....the "picket fence".

- Chose θ and γ , choice depends on
 - Efficiency
 - Space constraints
 - "Picket Fence" for Littrow configuration





Next Lecture:

How to achieve precice radial velocity measurements (PRV)

Tricks to improve efficiency: Overfill the Echelle





 $R \sim d_1/\phi$

For the same resolution you can increase the slit width and increase efficiency by 10-20%



Relation between blaze angle δ , grating normal, and angles of incidence and diffraction

Littrow configuration:	m λ = 2 σ sin δ	A increases	
$\theta = 0, \alpha = \beta = \delta$	A = 2 sin δ/λ	for increasing blaze angle	
	$R = 2d_1 \tan \delta/\phi D$		

R2 echelle, tan δ = 2, δ = 63.4° R4 echelle tan δ = 4, δ = 76°

At blaze peak $\alpha + \beta = 2\delta$ $m\lambda_b = 2 \sigma \sin \delta \cos \theta$ $\lambda_b = blaze wavelength$